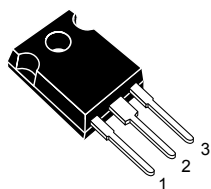
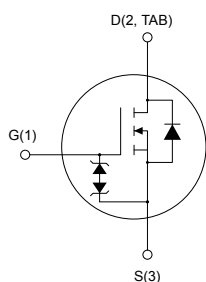




N-channel 600 V, 65 mΩ typ., 40 A MDmesh DM2 Power MOSFET in a TO-247 package



TO-247



AM15572V1_TAB



Product status link

[STW48N60DM2](#)

Product summary

Order code	STW48N60DM2
Marking	48N60DM2
Package	TO-247
Packing	Tube

Features

Order code	V _{DS}	R _{DS(on)} max.	I _D
STW48N60DM2	600 V	79 mΩ	40 A

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

Applications

- Switching applications

Description

This high-voltage N-channel Power MOSFET is part of the MDmesh DM2 fast-recovery diode series. It offers very low recovery charge (Q_{rr}) and time (t_{rr}) combined with low $R_{DS(on)}$, rendering it suitable for the most demanding high-efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	40	A
I_D	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	25	A
$I_{DM}^{(1)}$	Drain current (pulsed)	160	A
P_{TOT}	Total power dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	300	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	50	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^{\circ}\text{C}$
T_J	Operating junction temperature range		

1. Pulse width limited by safe operating area.

2. $I_{SD} \leq 40\text{ A}$, $di/dt \leq 900\text{ A}/\mu\text{s}$, $V_{DS}(\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$.

3. $V_{DD} \leq 480\text{ V}$.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	0.42	$^{\circ}\text{C}/\text{W}$
R_{thJA}	Thermal resistance, junction-to-ambient	50	$^{\circ}\text{C}/\text{W}$

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_J max.)	7	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	950	mJ

2 Electrical characteristics

($T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	600	-	-	V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$	-	-	1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$, $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$	-	-	100	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 25\text{ V}$	-	-	± 5	μA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 20\text{ A}$	-	65	79	m Ω

1. Specified by design, not tested in production.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	3250	-	pF
C_{oss}	Output capacitance		-	142	-	pF
C_{rss}	Reverse transfer capacitance		-	4.5	-	pF
$C_{oss\text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0\text{ V}$, $V_{DS} = 0\text{ to }480\text{ V}$	-	258	-	pF
R_g	Intrinsic gate resistance	$f = 1\text{ MHz}$, $I_D = 0\text{ A}$	-	4	-	Ω
Q_g	Total gate charge	$V_{DD} = 480\text{ V}$, $I_D = 40\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see the Figure 13. Test circuit for gate charge behavior)	-	70	-	nC
Q_{gs}	Gate-source charge		-	18	-	nC
Q_{gd}	Gate-drain charge		-	28	-	nC

1. $C_{oss\text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}$, $I_D = 20\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$	-	27	-	ns
t_r	Rise time		-	27	-	ns
$t_{d(off)}$	Turn-off delay time	(see the Figure 12. Test circuit for resistive load switching times and Figure 17. Switching time waveform)	-	131	-	ns
t_f	Fall time		-	9.8	-	ns


Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-	-	40	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-	-	160	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 40\text{ A}$, $V_{GS} = 0\text{ V}$	-	-	1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 40\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$	-	140	-	ns
Q_{rr}	Reverse recovery charge		-	0.7	-	μC
I_{RRM}	Reverse recovery current	(see the Figure 14. Test circuit for inductive load switching and diode recovery times)	-	10	-	A
t_{rr}	Reverse recovery time	$I_{SD} = 40\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$	-	256	-	ns
Q_{rr}	Reverse recovery charge		-	2.5	-	μC
I_{RRM}	Reverse recovery current	(see the Figure 14. Test circuit for inductive load switching and diode recovery times)	-	20	-	A

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

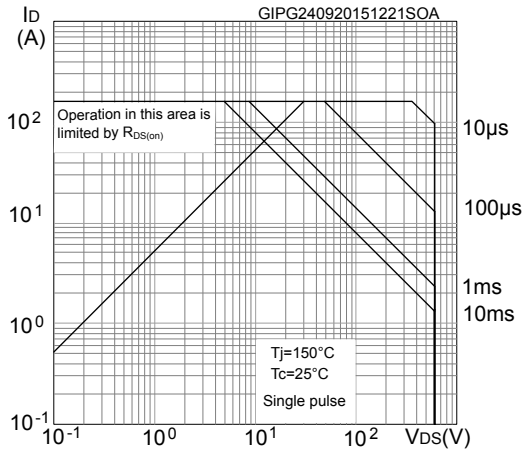
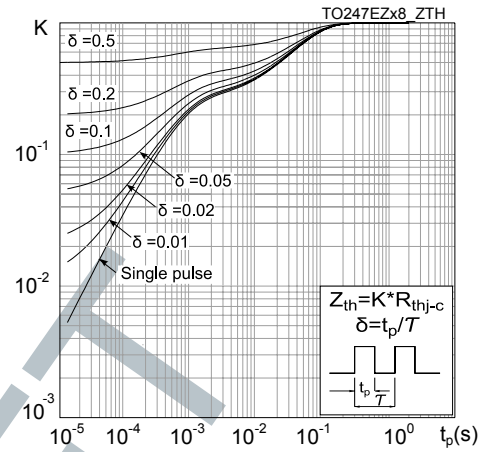
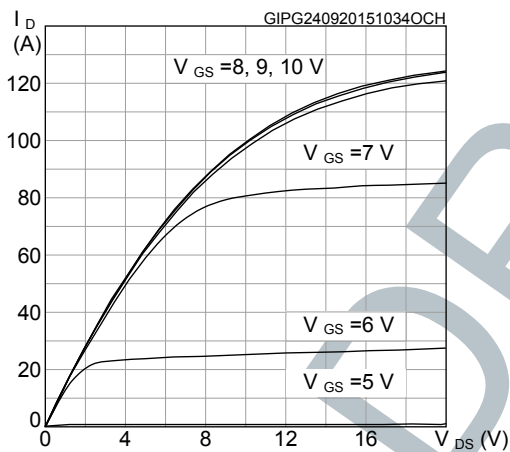
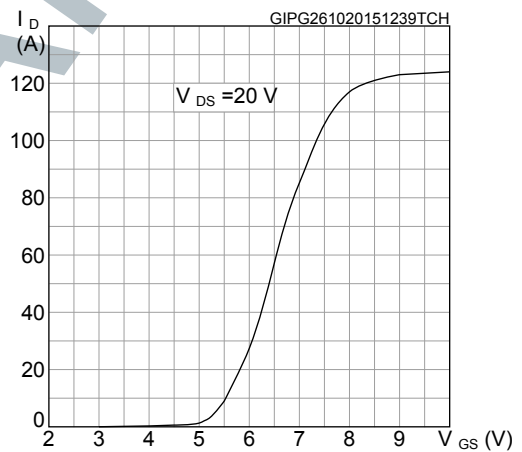
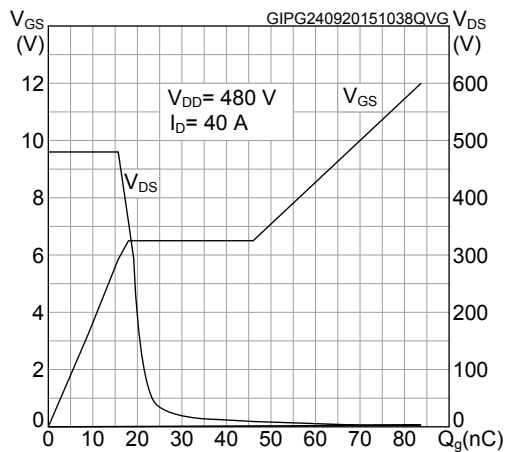
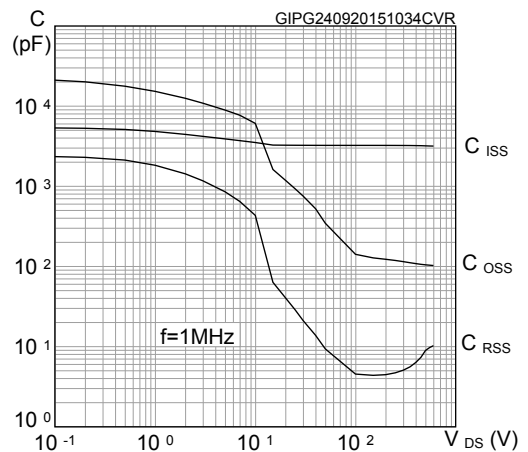
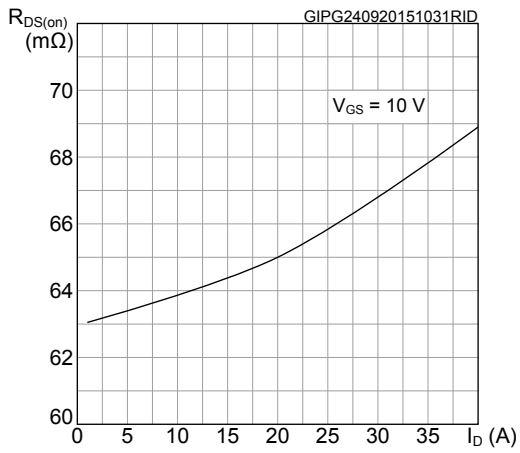
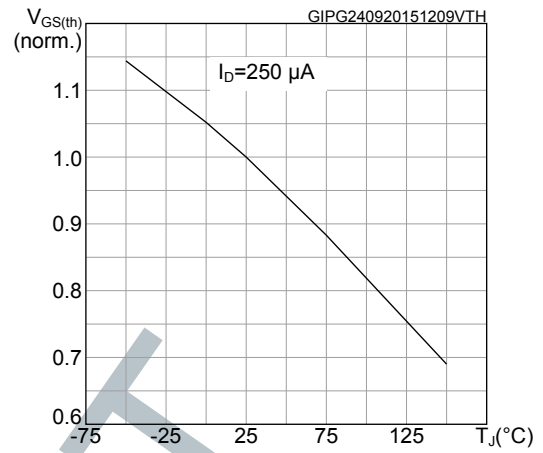
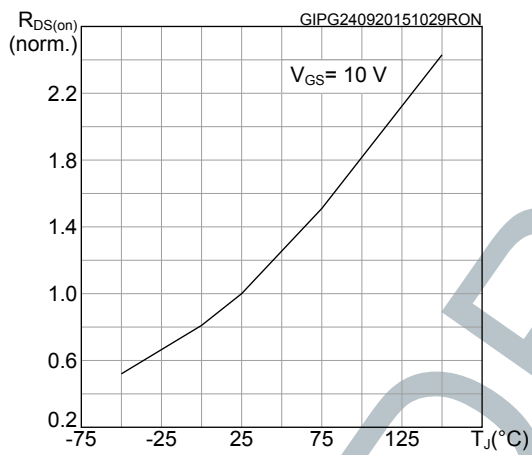
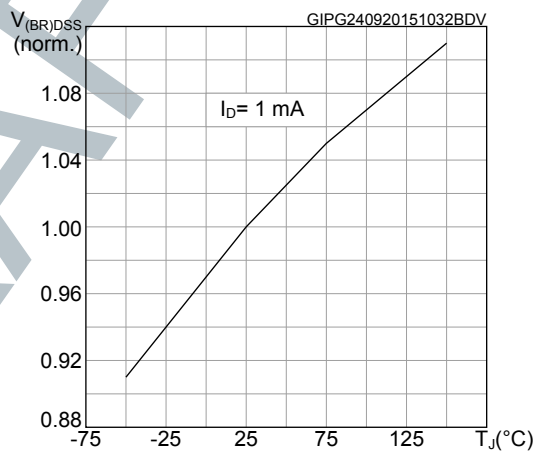
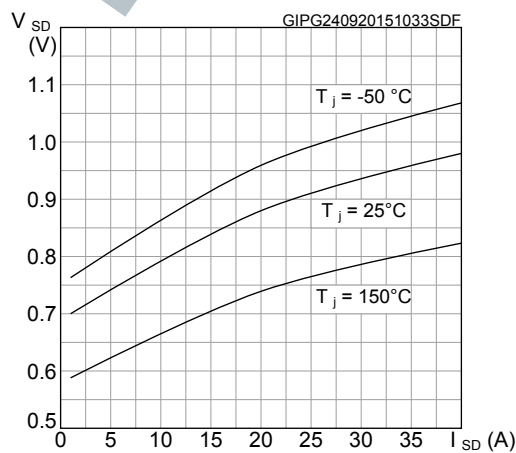
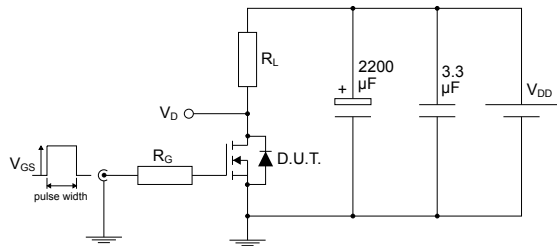
Figure 1. Safe operating area

Figure 2. Normalized transient thermal impedance

Figure 3. Typical output characteristics

Figure 4. Typical transfer characteristics

Figure 5. Typical gate charge characteristics

Figure 6. Typical capacitance characteristics


Figure 7. Typical drain-source on-resistance

Figure 8. Normalized gate threshold vs temperature

Figure 9. Normalized on-resistance vs temperature

Figure 10. Normalized breakdown voltage vs temperature

Figure 11. Typical reverse diode forward characteristics


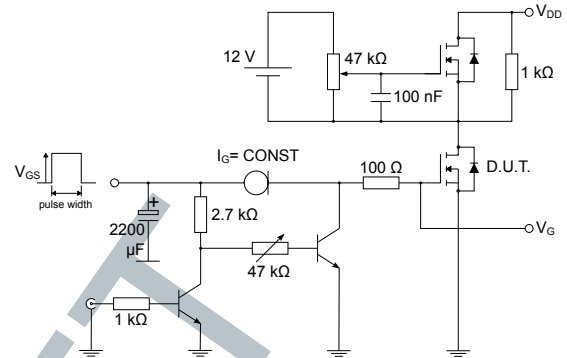
3 Test circuits

Figure 12. Test circuit for resistive load switching times



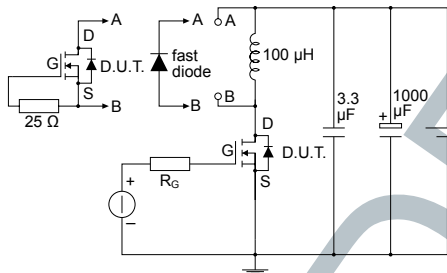
AM01468v1

Figure 13. Test circuit for gate charge behavior



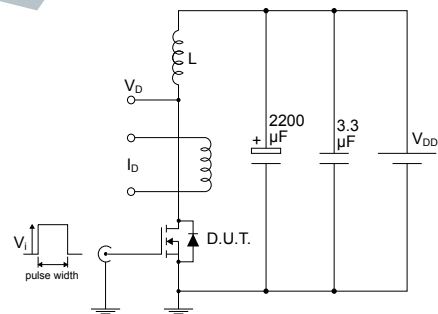
AM01469v1

Figure 14. Test circuit for inductive load switching and diode recovery times



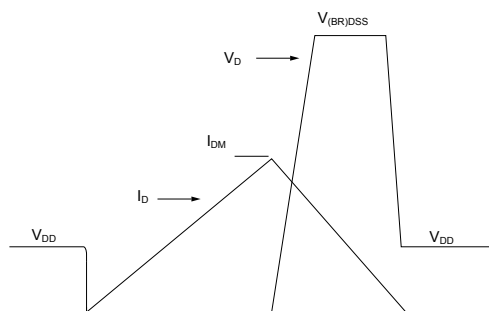
AM01470v1

Figure 15. Unclamped inductive load test circuit



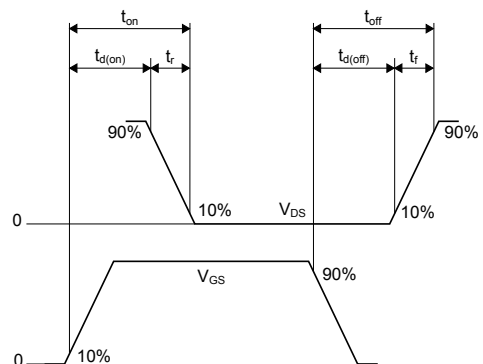
AM01471v1

Figure 16. Unclamped inductive waveform



AM01472v1

Figure 17. Switching time waveform



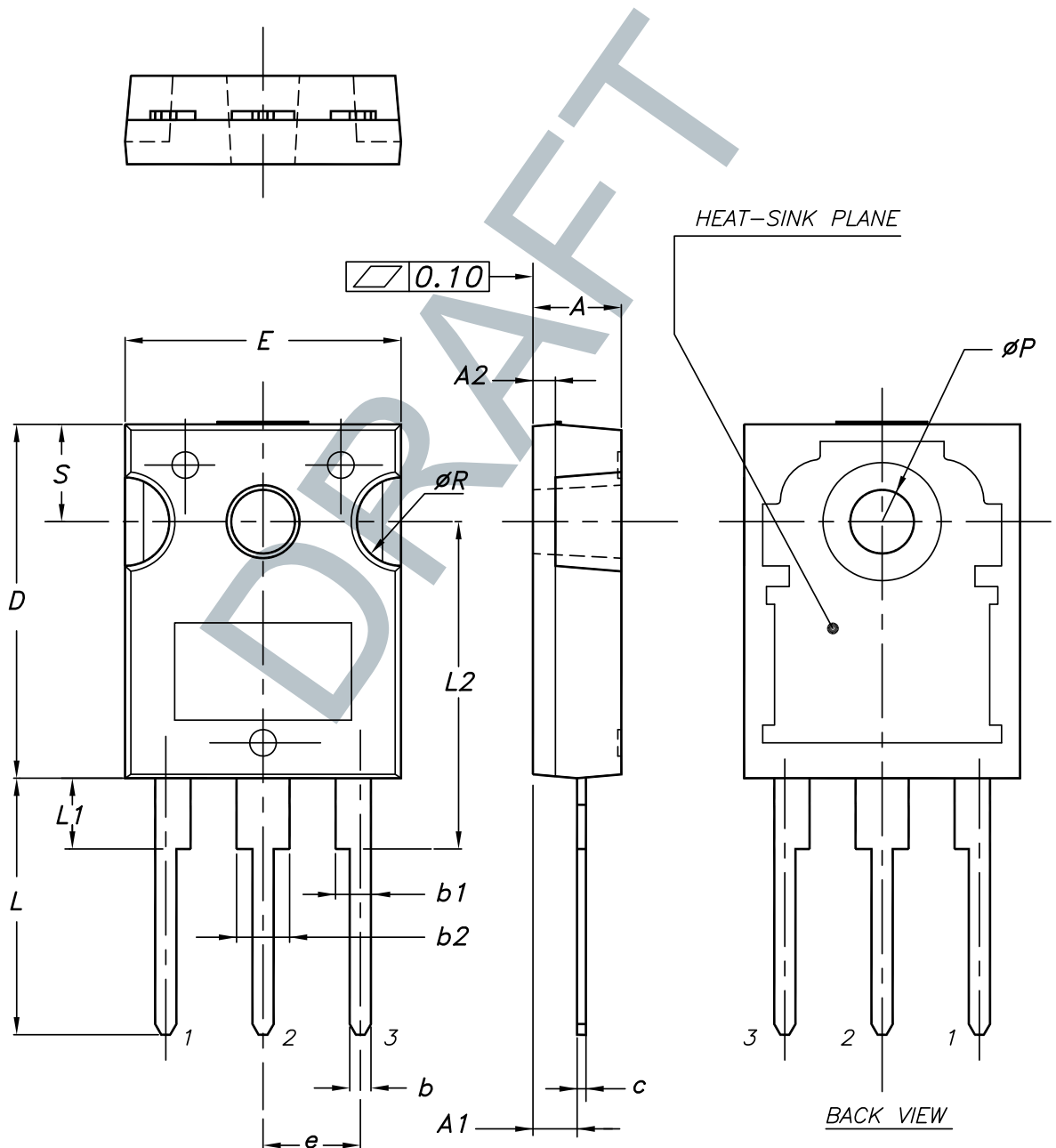
AM01473v1

4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-247 package information

Figure 18. TO-247 package outline



0075325_11


Table 8. TO-247 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
A2		1.27	
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Revision history

Table 9. Document revision history

Date	Version	Changes
21-Oct-2014	1	First release.
29-Oct-2015	2	Document status promoted from preliminary to production data. Modified: title. Modified: V_{DS} in cover page. Modified: Peak diode recovery voltage slope parameter value and <i>note 2</i>. Modified: $R_{thj-case}$ value in <i>Table 3: "Thermal data"</i>. Modified: the entire values in <i>Table 4: "Avalanche characteristics"</i>. Modified: I_{DSS}, I_{GSS} max values and $R_{DS(on)}$ typical value in <i>Table 5: "Static"</i>. Modified: the entire values in <i>Table 6: "Dynamic"</i>, <i>Table 7: "Switching times"</i> and <i>Table 8: "Source-drain diode"</i>. Added: <i>Table 9: "Gate-source Zener diode"</i>. Added: <i>Section 2.1: "Electrical characteristics (curves)"</i>. Minor text changes.
11-Dec-2025	3	Updated Section 4: Package information. Minor text changes.



Contents

1	Electrical ratings	2
2	Electrical characteristics.....	3
2.1	Electrical characteristics (curves)	5
3	Test circuits	7
4	Package information.....	8
4.1	TO-247 package information	8
	Revision history	10

DRAFT

**IMPORTANT NOTICE – READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice.

In the event of any conflict between the provisions of this document and the provisions of any contractual arrangement in force between the purchasers and ST, the provisions of such contractual arrangement shall prevail.

The purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgment.

The purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of the purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

If the purchasers identify an ST product that meets their functional and performance requirements but that is not designated for the purchasers' market segment, the purchasers shall contact ST for more information.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2025 STMicroelectronics – All rights reserved

DRAFT